## Notice of References Cited 10/563,087 Reexamination SUMIYA ET AL. Examiner SEYED MASOUD 1722 Reexamination SUMIYA ET AL. Page 1 of 1

Application/Control No.

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,830,269	11-1998	Kawase et al.	117/83
*	В	US-2003/0089299	05-2003	Obara et al.	117/2
*	С	US-2004/0089023	05-2004	Hiraiwa et al.	065/030.1
*	D	US-4,946,544	08-1990	Ejim, Theophilus I.	117/78
*	Ε	US-5,169,486	12-1992	Young et al.	117/83
*	F	US-2003/0154911	08-2003	Eissler, Elgin E.	117/81
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р	·				
	Q					
	R					
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under